



**■ PIN DESCRIPTIONS**

| Name   | Function  |
|--|---|
| <b>A0-A16 Address Input</b>  | These 17 address inputs select one of the 131,072 x 16-bit words in the RAM.  |
| <b><math>\overline{CE}</math> Chip Enable Input</b>                                      | $\overline{CE}$ is active LOW. Chip enables must be active when data read from or write to the device. If chip enable is not active, the device is deselected and is in a standby power mode. The DQ pins will be in the high impedance state when the device is deselected.  |
| <b><math>\overline{WE}</math> Write Enable Input</b>                                     | The write enable input is active LOW and controls read and write operations. With the chip selected, when $\overline{WE}$ is HIGH and $\overline{OE}$ is LOW, output data will be present on the DQ pins; when $\overline{WE}$ is LOW, the data present on the DQ pins will be written into the selected memory location. |
| <b><math>\overline{OE}</math> Output Enable Input</b>                                    | The output enable input is active LOW. If the output enable is active while the chip is selected and the write enable is inactive, data will be present on the DQ pins and they will be enabled. The DQ pins will be in the high impedance state when $\overline{OE}$ is inactive.  |
| <b><math>\overline{LB}</math> and <math>\overline{UB}</math> Data Byte Control Input</b> | Lower byte and upper byte data input/output control pins.   |
| <b>DQ0 - DQ15 Data Input/Output Ports</b>  | These 16 bi-directional ports are used to read data from or write data into the RAM.  |
| <b>Vcc</b>   | Power Supply  |
| <b>Gnd</b>   | Ground  |

**■ TRUTH TABLE**

| MODE                         | $\overline{CE}$ | $\overline{WE}$ | $\overline{OE}$ | $\overline{LB}$ | $\overline{UB}$ | DQ0~DQ7 | DQ8~DQ15 | Vcc CURRENT           |
|------------------------------|-----------------|-----------------|-----------------|-----------------|-----------------|---------|----------|-----------------------|
| Not selected<br>(Power Down) | H               | X               | X               | X               | X               | High Z  | High Z   | $I_{CCSB}, I_{CCSB1}$ |
| Output Disabled              | L               | H               | H               | X               | X               | High Z  | High Z   | $I_{CC}$              |
| Read                         | L               | H               | L               | L               | L               | Dout    | Dout     | $I_{CC}$              |
|                              |                 |                 |                 | H               | L               | High Z  | Dout     | $I_{CC}$              |
|                              |                 |                 |                 | L               | H               | Dout    | High Z   | $I_{CC}$              |
| Write                        | L               | L               | X               | L               | L               | Din     | Din      | $I_{CC}$              |
|                              |                 |                 |                 | H               | L               | X       | Din      | $I_{CC}$              |
|                              |                 |                 |                 | L               | H               | Din     | X        | $I_{CC}$              |

**■ ABSOLUTE MAXIMUM RATINGS<sup>(1)</sup>**

| SYMBOL            | PARAMETER                            | RATING                       | UNITS |
|-------------------|--------------------------------------|------------------------------|-------|
| V <sub>TERM</sub> | Terminal Voltage with Respect to GND | -0.5 to V <sub>CC</sub> +0.5 | V     |
| T <sub>BIAS</sub> | Temperature Under Bias               | -40 to +125                  | °C    |
| T <sub>STG</sub>  | Storage Temperature                  | -60 to +150                  | °C    |
| P <sub>T</sub>    | Power Dissipation                    | 1.0                          | W     |
| I <sub>OUT</sub>  | DC Output Current                    | 20                           | mA    |

1. Stresses greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

**■ OPERATING RANGE**

| RANGE      | AMBIENT TEMPERATURE | V <sub>CC</sub> |
|------------|---------------------|-----------------|
| Commercial | 0 °C to +70 °C      | 2.7V ~ 3.6V     |
| Industrial | -40 °C to +85 °C    | 2.7V ~ 3.6V     |

**■ CAPACITANCE <sup>(1)</sup> (TA = 25°C, f = 1.0 MHz)**

| SYMBOL          | PARAMETER                | CONDITIONS           | MAX. | UNIT |
|-----------------|--------------------------|----------------------|------|------|
| C <sub>IN</sub> | Input Capacitance        | V <sub>IN</sub> =0V  | 6    | pF   |
| C <sub>DQ</sub> | Input/Output Capacitance | V <sub>I/O</sub> =0V | 8    | pF   |

1. This parameter is guaranteed and not tested.

**■ DC ELECTRICAL CHARACTERISTICS ( TA = 0 to + 70°C )**

| PARAMETER NAME     | PARAMETER                                    | TEST CONDITIONS  | MIN. | TYP. <sup>(1)</sup> | MAX.                 | UNITS |
|--------------------|--|--|------|---------------------|----------------------|-------|
| V <sub>IL</sub>    | Guaranteed Input Low Voltage <sup>(2)</sup>  | V <sub>CC</sub> =3.0V  | -0.5 | --                  | 0.8                  | V     |
| V <sub>IH</sub>    | Guaranteed Input High Voltage <sup>(2)</sup> | V <sub>CC</sub> =3.0V  | 2.0  | --                  | V <sub>CC</sub> +0.2 | V     |
| I <sub>IL</sub>    | Input Leakage Current                        | V <sub>CC</sub> = Max, V <sub>IN</sub> = 0V to V <sub>CC</sub>   | --   | --                  | 1                    | uA    |
| I <sub>OL</sub>    | Output Leakage Current                       | V <sub>CC</sub> = Max, $\overline{CE} = V_{IH}$ , or $\overline{OE} = V_{IH}$ , V <sub>I/O</sub> = 0V to V <sub>CC</sub> | --   | --                  | 1                    | uA    |
| V <sub>OL</sub>    | Output Low Voltage                           | V <sub>CC</sub> = Max, I <sub>OL</sub> = 2mA   | --   | --                  | 0.4                  | V     |
| V <sub>OH</sub>    | Output High Voltage                          | V <sub>CC</sub> = Min, I <sub>OH</sub> = -1mA  | 2.4  | --                  | --                   | V     |
| I <sub>CC</sub>    | Operating Power Supply Current               | $\overline{CE} = V_{IL}$ , I <sub>DQ</sub> = 0mA, F = F <sub>max</sub> <sup>(3)</sup>                                    | --   | --                  | 25                   | mA    |
| I <sub>CCSB</sub>  | Standby Current-TTL                          | $\overline{CE} = V_{IH}$ , I <sub>DQ</sub> = 0mA   | --   | --                  | 1                    | mA    |
| I <sub>CCSB1</sub> | Standby Current-CMOS                         | $\overline{CE} \geq V_{CC} - 0.2V$ ,<br>V <sub>IN</sub> $\geq V_{CC} - 0.2V$ or V <sub>IN</sub> $\leq 0.2V$              | --   | 0.15                | 8                    | uA    |

1. Typical characteristics are at TA = 25°C.

2. These are absolute values with respect to device ground and all overshoots due to system or tester noise are included.

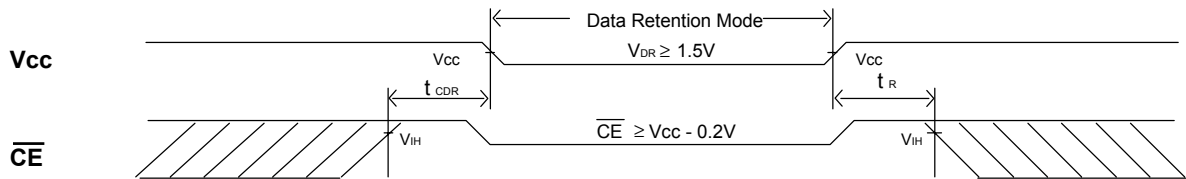
3. F<sub>max</sub> = 1/t<sub>RC</sub>.

**■ DATA RETENTION CHARACTERISTICS ( TA = 0 to + 70°C )**

| SYMBOL            | PARAMETER                            | TEST CONDITIONS   | MIN.                           | TYP. <sup>(1)</sup> | MAX. | UNITS |
|-------------------|--------------------------------------|---|--------------------------------|---------------------|------|-------|
| V <sub>DR</sub>   | V <sub>CC</sub> for Data Retention   | $\overline{CE} \geq V_{CC} - 0.2V$<br>V <sub>IN</sub> $\geq V_{CC} - 0.2V$ or V <sub>IN</sub> $\leq 0.2V$ | 1.5                            | --                  | --   | V     |
| I <sub>CCDR</sub> | Data Retention Current               | $\overline{CE} \geq V_{CC} - 0.2V$<br>V <sub>IN</sub> $\geq V_{CC} - 0.2V$ or V <sub>IN</sub> $\leq 0.2V$ | --                             | 0.1                 | 5    | uA    |
| t <sub>CDR</sub>  | Chip Deselect to Data Retention Time | See Retention Waveform  | 0                              | --                  | --   | ns    |
| t <sub>R</sub>    | Operation Recovery Time              |   | T <sub>RC</sub> <sup>(2)</sup> | --                  | --   | ns    |

1. V<sub>CC</sub> = 1.5V, T<sub>A</sub> = + 25°C

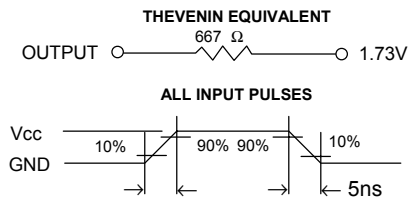
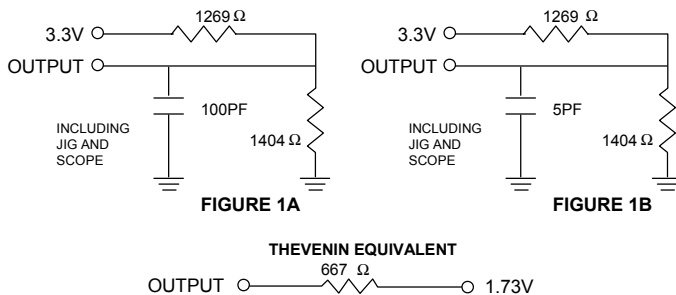
2. t<sub>RC</sub> = Read Cycle Time

**■ LOW  $V_{CC}$  DATA RETENTION WAVEFORM (  $\overline{CE}$  Controlled )**

**■ AC TEST CONDITIONS**

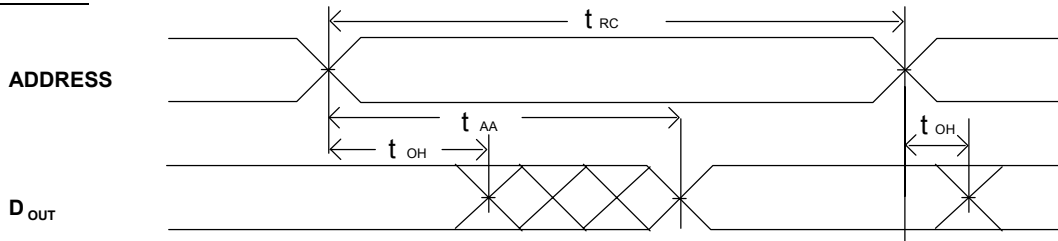
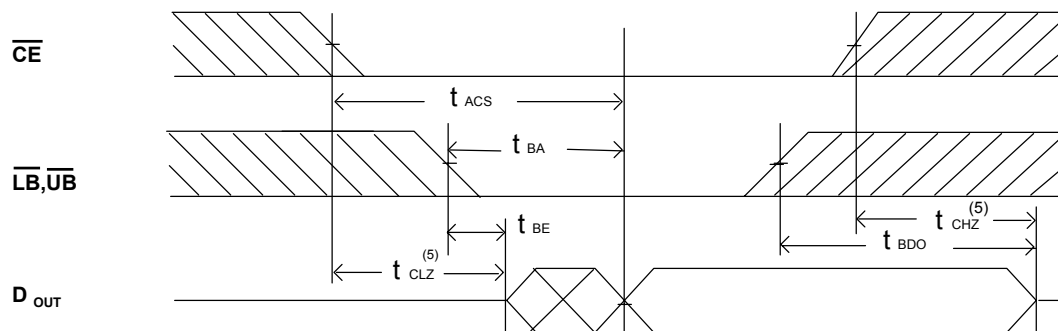
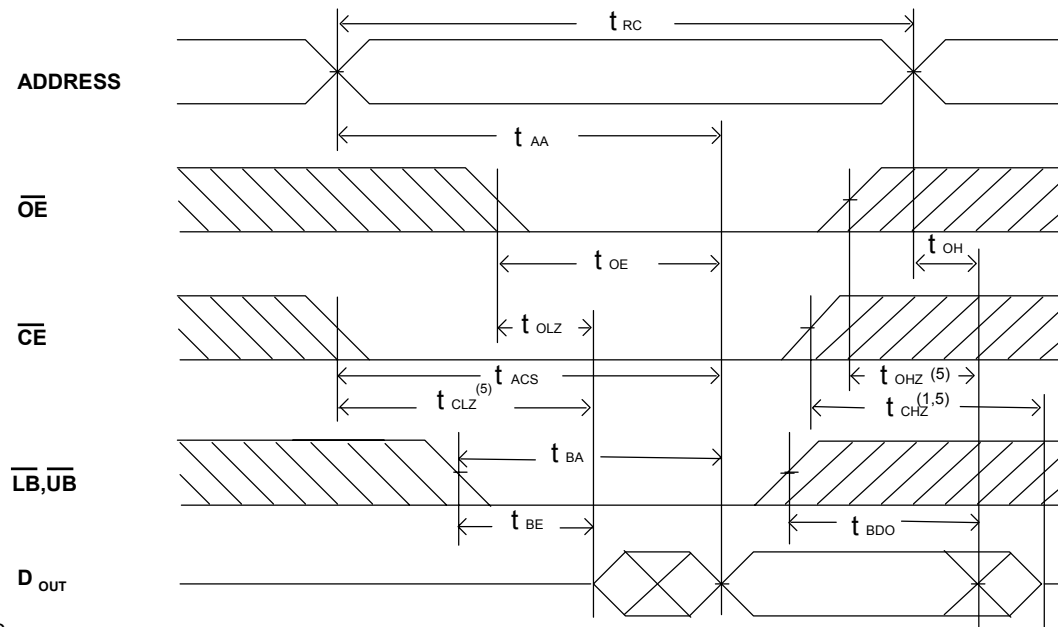
|   |             |
|---|-------------|
| Input Pulse Levels                      | $V_{CC}/0V$ |
| Input Rise and Fall Times               | 5ns         |
| Input and Output Timing Reference Level | $0.5V_{CC}$ |

**■ KEY TO SWITCHING WAVEFORMS**

| WAVEFORM | INPUTS                           | OUTPUTS                                   |
|----------|----------------------------------|---|
|          | MUST BE STEADY                   | MUST BE STEADY                            |
|          | MAY CHANGE FROM H TO L           | WILL BE CHANGE FROM H TO L                |
|          | MAY CHANGE FROM L TO H           | WILL BE CHANGE FROM L TO H                |
|          | DON'T CARE: ANY CHANGE PERMITTED | CHANGE: STATE UNKNOWN                     |
|          | DOES NOT APPLY                   | CENTER LINE IS HIGH IMPEDANCE "OFF" STATE |

**■ AC TEST LOADS AND WAVEFORMS**

**FIGURE 2**
**■ AC ELECTRICAL CHARACTERISTICS (  $T_A = 0$  to  $+70^\circ C$  ,  $V_{CC} = 3.0V$  )  
READ CYCLE**

| JEDEC PARAMETER NAME | PARAMETER NAME | DESCRIPTION   | BS616LV2010-70 |      |      | BS616LV2010-10 |      |      | UNIT |
|----------------------|----------------|---|----------------|------|------|----------------|------|------|------|
|                      |                |   | MIN.           | TYP. | MAX. | MIN.           | TYP. | MAX. |      |
| $t_{AVAX}$           | $t_{RC}$       | Read Cycle Time   | 70             | --   | --   | 100            | --   | --   | ns   |
| $t_{AVQV}$           | $t_{AA}$       | Address Access Time   | --             | --   | 70   | --             | --   | 100  | ns   |
| $t_{ELQV}$           | $t_{ACS}$      | Chip Select Access Time ( $\overline{CE}$ )                           | --             | --   | 70   | --             | --   | 100  | ns   |
| $t_{BA}$             | $t_{BA}$       | Data Byte Control Access Time ( $\overline{LB}, \overline{UB}$ )      | --             | --   | 40   | --             | --   | 50   | ns   |
| $t_{GLQV}$           | $t_{OE}$       | Output Enable to Output Valid   | --             | --   | 50   | --             | --   | 60   | ns   |
| $t_{E1LQX}$          | $t_{CLZ}$      | Chip Select to Output Low Z ( $\overline{CE}$ )                       | 10             | --   | --   | 15             | --   | --   | ns   |
| $t_{BE}$             | $t_{BE}$       | Data Byte Control to Output Low Z ( $\overline{LB}, \overline{UB}$ )  | 10             | --   | --   | 15             | --   | --   | ns   |
| $t_{GLQX}$           | $t_{OLZ}$      | Output Enable to Output in Low Z                                      | 10             | --   | --   | 15             | --   | --   | ns   |
| $t_{EHQZ}$           | $t_{CHZ}$      | Chip Deselect to Output in High Z ( $\overline{CE}$ )                 | 0              | --   | 35   | 0              | --   | 40   | ns   |
| $t_{BDO}$            | $t_{BDO}$      | Data Byte Control to Output High Z ( $\overline{LB}, \overline{UB}$ ) | 0              | --   | 30   | 0              | --   | 35   | ns   |
| $t_{GHQZ}$           | $t_{OHZ}$      | Output Disable to Output in High Z                                    | 0              | --   | 30   | 0              | --   | 35   | ns   |
| $t_{AXOX}$           | $t_{OH}$       | Output Disable to Address Change                                      | 10             | --   | --   | 15             | --   | --   | ns   |

**■ SWITCHING WAVEFORMS (READ CYCLE)**
**READ CYCLE1 (1,2,4)**

**READ CYCLE2 (1,3,4)**

**READ CYCLE3 (1,4)**

**NOTES:**

1.  $\overline{WE}$  is high for read Cycle.
2. Device is continuously selected when  $\overline{CE} = V_{IL}$ .
3. Address valid prior to or coincident with  $\overline{CE}$  transition low.
4.  $\overline{OE} = V_{IL}$ .
5. Transition is measured  $\pm 500\text{mV}$  from steady state with  $C_L = 5\text{pF}$  as shown in Figure 1B. The parameter is guaranteed but not 100% tested.

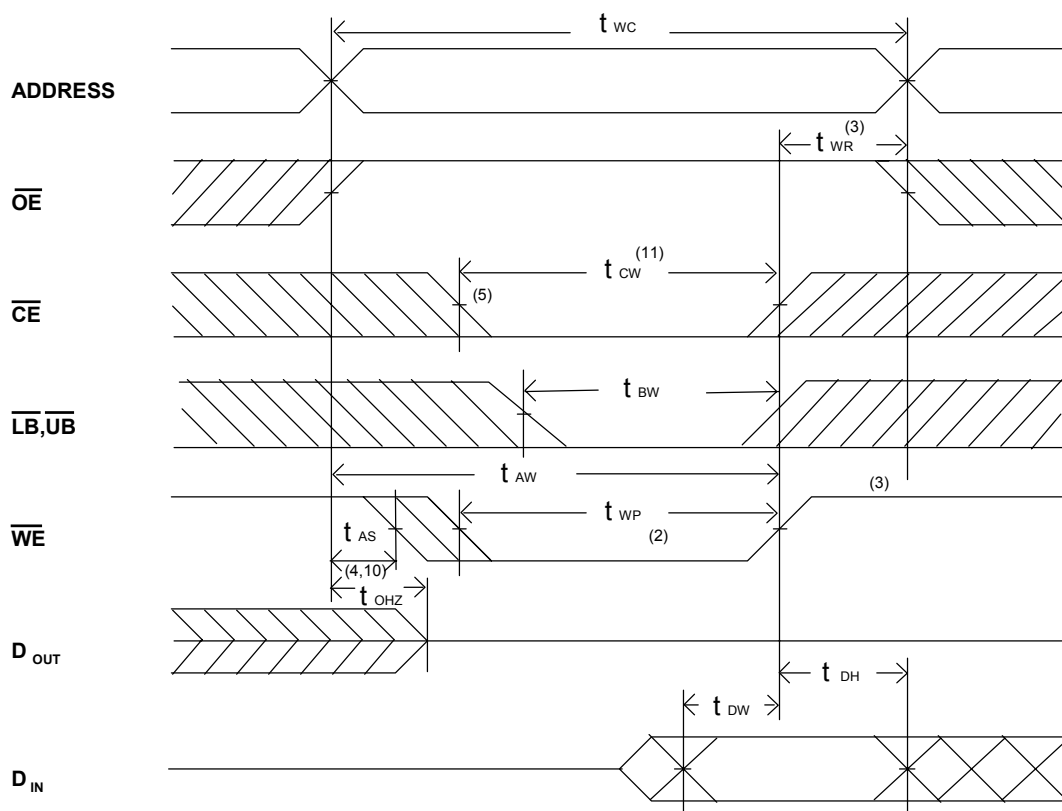
## ■ AC ELECTRICAL CHARACTERISTICS ( TA = 0 to + 70°C , Vcc = 3.0V )

### WRITE CYCLE

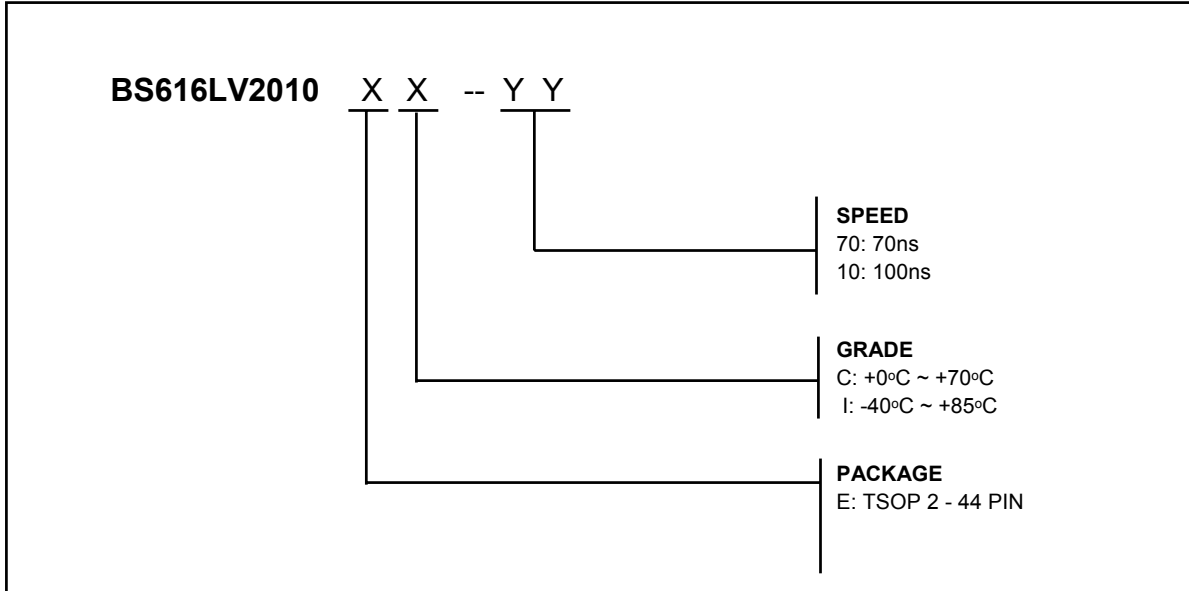
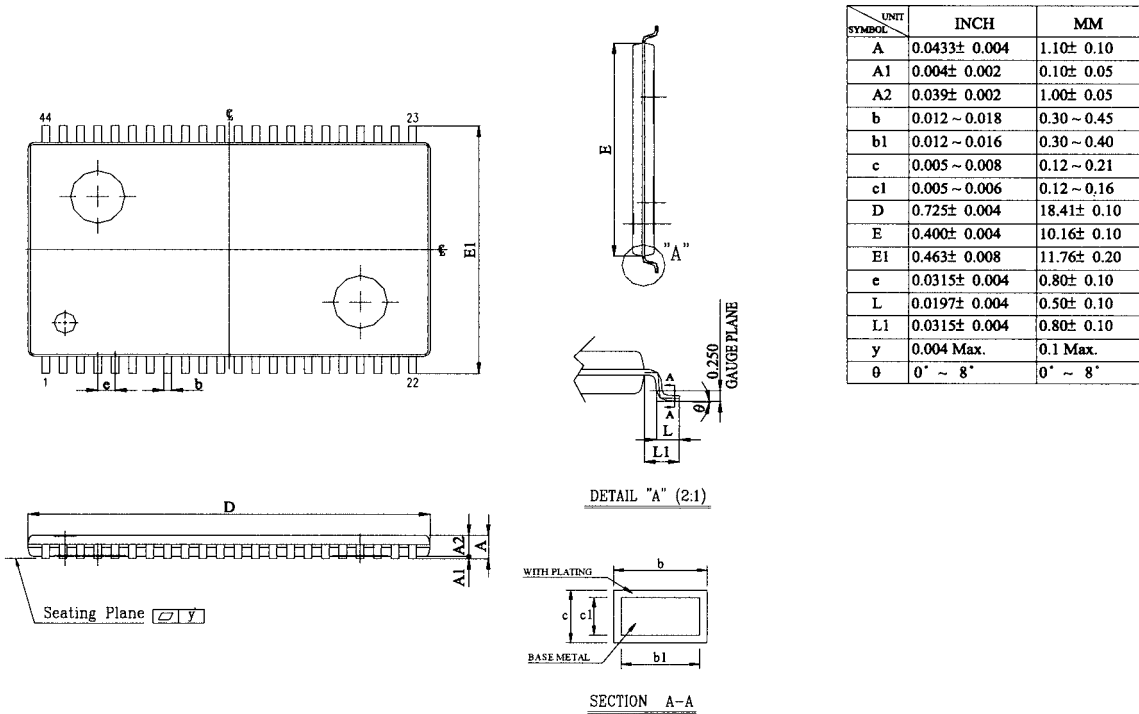
| JEDEC<br>PARAMETER<br>NAME | PARAMETER<br>NAME | DESCRIPTION   | BS616LV2010-70 |      |      | BS616LV2010-10 |      |      | UNIT |
|----------------------------|-------------------|---|----------------|------|------|----------------|------|------|------|
|                            |                   |   | MIN.           | TYP. | MAX. | MIN.           | TYP. | MAX. |      |
| $t_{AVAX}$                 | $t_{WC}$          | Write Cycle Time  | 70             | --   | --   | 100            | --   | --   | ns   |
| $t_{E1LWH}$                | $t_{CW}$          | Chip Select to End of Write   | 70             | --   | --   | 100            | --   | --   | ns   |
| $t_{AVWL}$                 | $t_{AS}$          | Address Setup Time  | 0              | --   | --   | 0              | --   | --   | ns   |
| $t_{AVWH}$                 | $t_{AW}$          | Address Valid to End of Write   | 70             | --   | --   | 100            | --   | --   | ns   |
| $t_{WLWH}$                 | $t_{WP}$          | Write Pulse Width   | 50             | --   | --   | 70             | --   | --   | ns   |
| $t_{WHAX}$                 | $t_{WR}$          | Write recovery Time<br>( $\overline{CE}, \overline{WE}$ )               | 0              | --   | --   | 0              | --   | --   | ns   |
| $t_{BW}$                   | $t_{BW}$          | Date Byte Control to End of Write<br>( $\overline{LB}, \overline{UB}$ ) | 60             | --   | --   | 80             | --   | --   | ns   |
| $t_{WLQZ}$                 | $t_{WHZ}$         | Write to Output in High Z   | 0              | --   | 30   | 0              | --   | 40   | ns   |
| $t_{DVWH}$                 | $t_{DW}$          | Data to Write Time Overlap  | 30             | --   | --   | 40             | --   | --   | ns   |
| $t_{WHDX}$                 | $t_{DH}$          | Data Hold from Write Time   | 0              | --   | --   | 0              | --   | --   | ns   |
| $t_{GHQZ}$                 | $t_{OHZ}$         | Output Disable to Output in High Z                                      | 0              | --   | 30   | 0              | --   | 40   | ns   |
| $t_{WHOX}$                 | $t_{OW}$          | End of Write to Output Active   | 5              | --   | --   | 10             | --   | --   | ns   |

## ■ SWITCHING WAVEFORMS (WRITE CYCLE)

### WRITE CYCLE1<sup>(1)</sup>





**ORDERING INFORMATION**

**PACKAGE DIMENSIONS**

**TSOP2-44**



***REVISION HISTORY***

| <b>Revision</b> | <b>Description</b>             | <b>Date</b>          | <b>Note</b> |
|-----------------|--------------------------------|----------------------|-------------|
| <b>2.2</b>      | <b>2001 Data Sheet release</b> | <b>Apr. 15, 2001</b> |             |

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